

10/512082

DRAFTING DATE: 10 NOV 2004
SHEET 1 OF 1

Form PTO 1449 (Modified) ▼ LIST OF REFERENCES CITED BY APPLICANT		ATTY DOCKET NO. 261333US2PCT		SERIAL NO. New U.S. PCT Application Based on PCT/JP02/06127		
		APPLICANT Takao SAWADA, et al.				
		FILING DATE Herewith		GROUP 2879		
		U.S. PATENT DOCUMENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS SUB CLASS	FILING DATE IF APPROPRIATE
	AA					
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					
	AL					
	AM					
	AN					
FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO	
PM	AO	2000-40461	02/08/00	JP		NO
	AP	58-189940	11/05/83	JP		NO
	AQ	61-4133	01/10/86	JP		NO
	AR	9-190761	07/22/97	JP (equivalent of US 6091189)		NO
	AS	2000-251613	09/14/00	JP		NO
	AT	9-106750	04/22/97	JP (equivalent of US 5118984)		NO
	AU	2758244	03/13/98	JP (equivalent of US 5118984)		NO
PM	AV	54-83360	07/03/79	JP (equivalent of US 4273683)		NO
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)						
PM	AW	HAYASHIDA, Y. et al. "An Analysis of Cut-Off Voltage Drift in the Oxide Cathode Life", Electronics Research Laboratory, Matsushita Electronics Corporation, pages 67-72, with English abstract 1995				
	AX					
	AY					
	AZ				<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Peter Macchiarolo/ (09/16/2006)					Date Considered 09/16/2006	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						